华润微电子(重庆)有限公司

CRSQ027N10NZ

SkyMOS1 N-MOSFET 100V, 2.4mΩ, 240A

Features

- Uses CRM(CQ) advanced SkyMOS1 technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent Q_gx$R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria
- 175°C Operating Temperature

Product Summary

V_{DS}	100V
$R_{DS(on)}$	2.4mΩ
I_D	240A
I_D(silicon limit)	270A

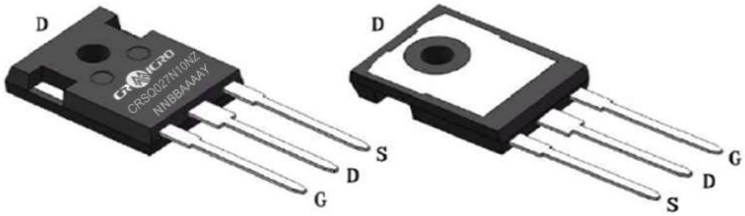
Applications

- Motor control and drive
- Battery management
- UPS (Uninterrupible Power Supplies)

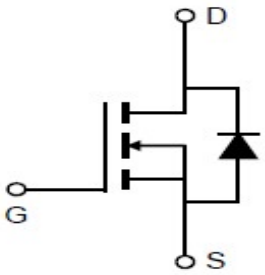
100% Avalanche Tested
100% DVDS Tested

RoHS HF

TO-247



CRSQ027N10NZ



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRSQ027N10NZ	CRSQ027N10NZ	TO-247	Tube	N/A	N/A	25pcs

Absolute Maximum Ratings

Parameter	**Symbol**	**Value**	**Unit**
Drain-source voltage	V_{DS}	100	V
Continuous drain current T_C = 25°C (Silicon limit) T_C = 25°C (Package limit) T_C = 100°C (Silicon limit)	I_D	 270 240 189	A
Pulsed drain current (T_C = 25°C, t_p limited by T_{jmax})	$I_{D\ pulse}$	960	A
Avalanche energy, single pulse (L=0.5mH, Rg=25Ω)[1]	E_{AS}	529	mJ
Gate-Source voltage	V_{GS}	±20	V
Power dissipation (T_C = 25°C)	P_{tot}	417	W
Operating junction and storage temperature	T_j , T_{stg}	-55...+175	°C

Notes:1.EAS was tested at Tj = 25℃, ID = 46A.

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Thermal Resistance

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Thermal resistance, junction – case.	R_{thJC}	-	0.28	0.36	°C/W	
Thermal resistance, junction – ambient(min.	R_{thJA}	-	-	62	°C/W	

Electrical Characteristic (at Tj = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Static Characteristic						
Drain-source breakdown voltage	BV_{DSS}	100	-	-	V	V_{GS}=0V, I_D=250uA
Gate threshold voltage	$V_{GS(th)}$	2.0	3.0	4.0	V	V_{DS}=V_{GS},I_D=250uA
Zero gate voltage drain current	I_{DSS}	-	0.05	1	μA	V_{DS}=100V,V_{GS}=0V T_j=25°C
		-	-	10		T_j=125°C
Gate-source leakage current	I_{GSS}	-	±10	±100	nA	V_{GS}=±20V,V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	-	2.4	3.0	mΩ	V_{GS}=10V, I_D=90A
Transconductance	g_{fs}	-	197.2	-	S	V_{DS}=5V,I_D=90A
Dynamic Characteristic						
Input Capacitance	C_{iss}	7570	11355	17033	pF	V_{GS}=0V, V_{DS}=50V, f=1MHz
Output Capacitance	C_{oss}	964	1446	2169		
Reverse Transfer Capacitance	C_{rss}	36	54	81		
Gate Total Charge	Q_G	112.7	169	253.5	nC	V_{GS}=10V, V_{DS}=50V, I_D=90A
Gate-Source charge	Q_{gs}	44.7	67	100.5		
Gate-Drain charge	Q_{gd}	20	30	45		
Turn-on delay time	$t_{d(on)}$	23.3	35	52.5	ns	V_{GS}=10V, V_{DD}=50V, R_{G_ext}=3.0Ω
Rise time	t_r	74	111	166.5		
Turn-off delay time	$t_{d(off)}$	56	84	126		
Fall time	t_f	74.7	112	168		
Gate resistance	R_G	-	1.8	5.5	Ω	V_{GS}=0V, V_{DS}=0V, f=1MHz

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Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	-	0.9	1.4	V	V_{GS}=0V,I_{SD}=90A
Body Diode Continuous Forward Current	I_S	-	-	240	A	T_C = 25°C
Body Diode Pulsed Current	$I_{S\ pulse}$	-	-	960	A	T_C = 25°C
Body Diode Reverse Recovery Time	t_{rr}	50.5	101	202	ns	I_F=90A, dI/dt=100A/μs
Body Diode Reverse Recovery Charge	Q_{rr}	169	338	676	nC	

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Typical Performance Characteristics

Fig 1: Output Characteristics

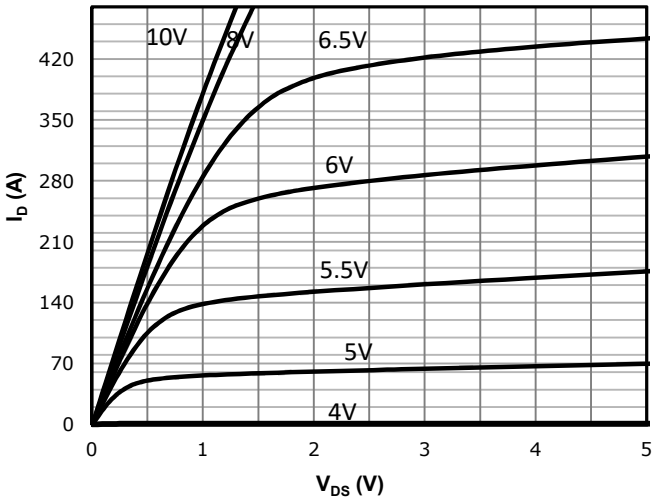


Fig 2: Transfer Characteristics

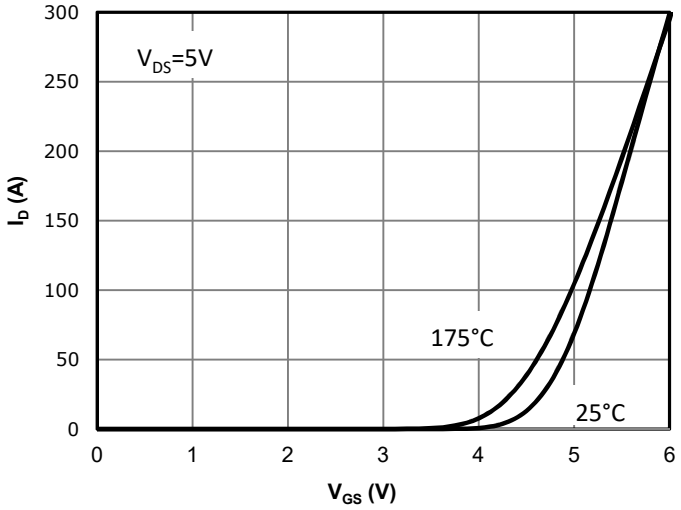


Fig 3: Rds(on) vs Drain Current and Gate Voltage

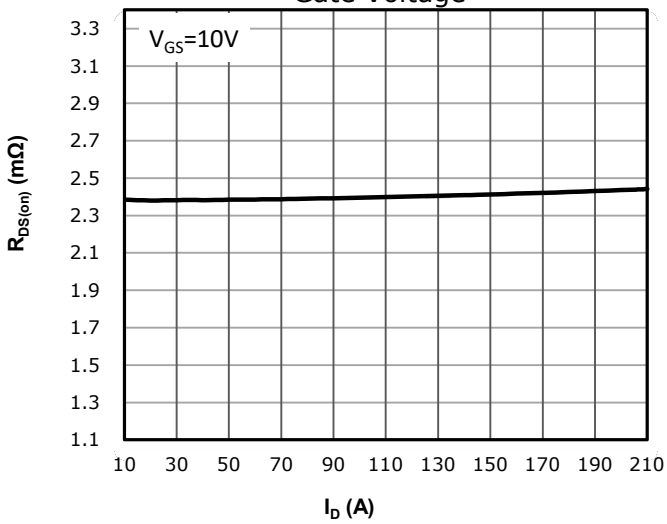


Fig 4: Rds(on) vs Gate Voltage

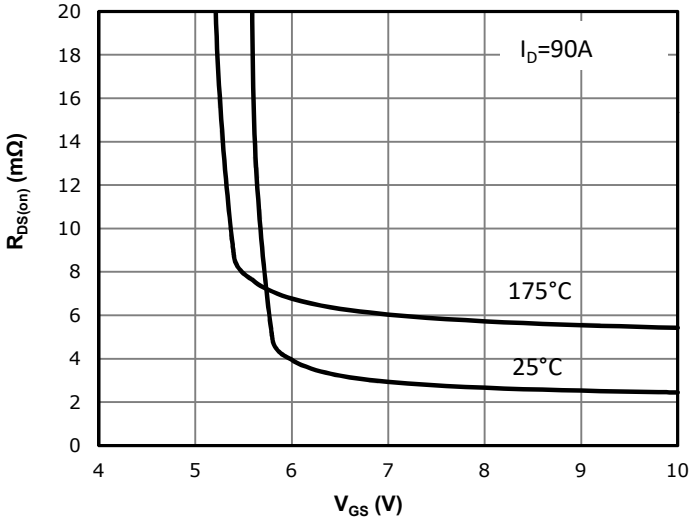


Fig 5: Rds(on) vs. Temperature

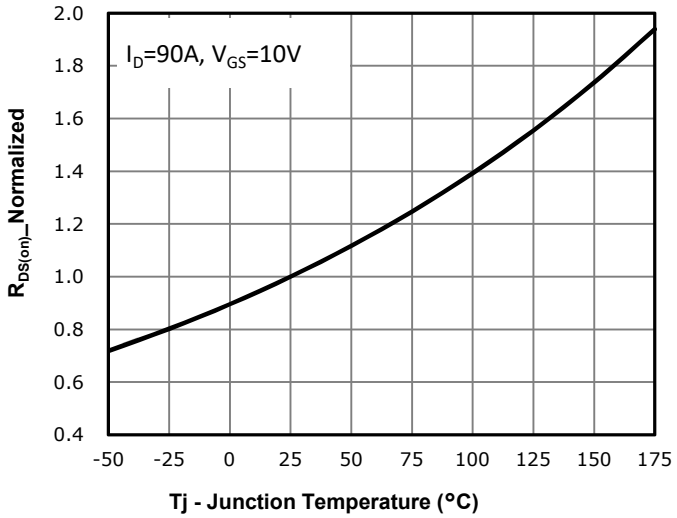
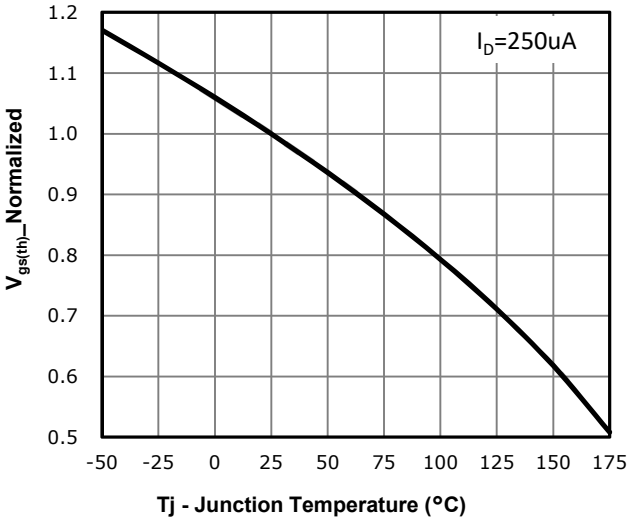


Fig 6: Vgs(th) vs. Temperature



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Fig 7: BVdss vs. Temperature

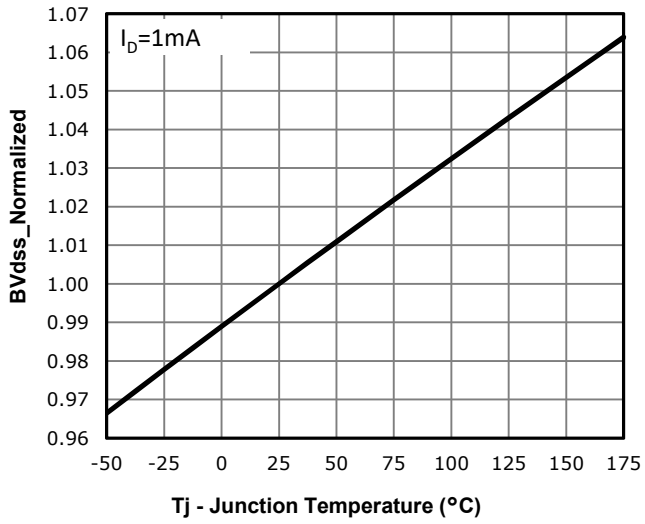


Fig 8: Capacitance Characteristics

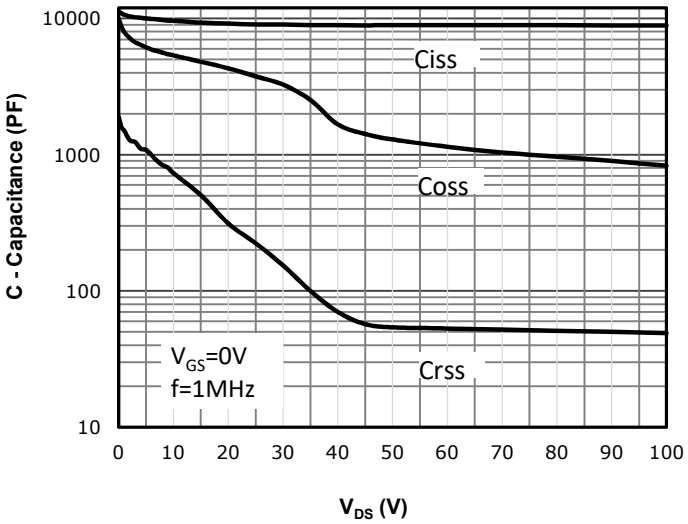


Fig 9: Gate Charge Characteristics

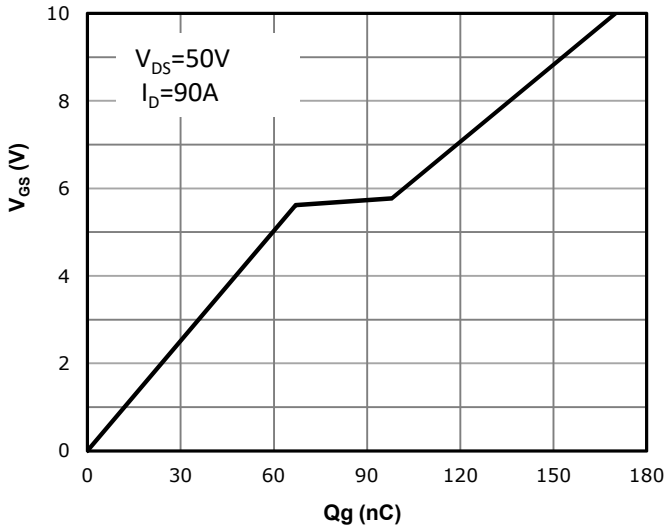


Fig 10: Body-diode Forward Characteristics

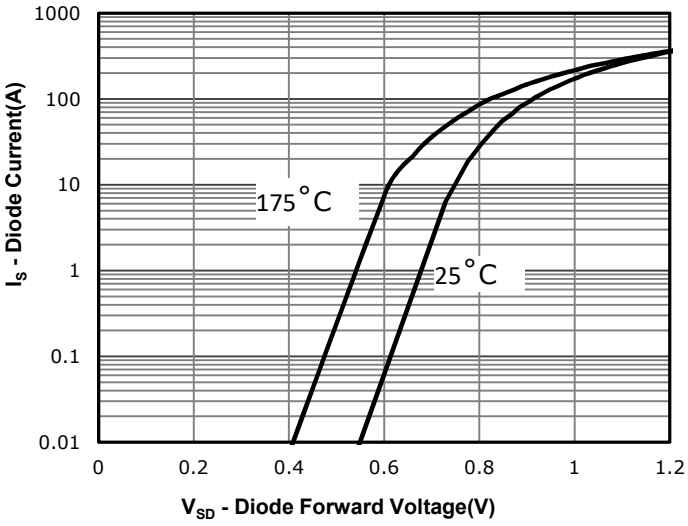


Fig 11: Power Dissipation

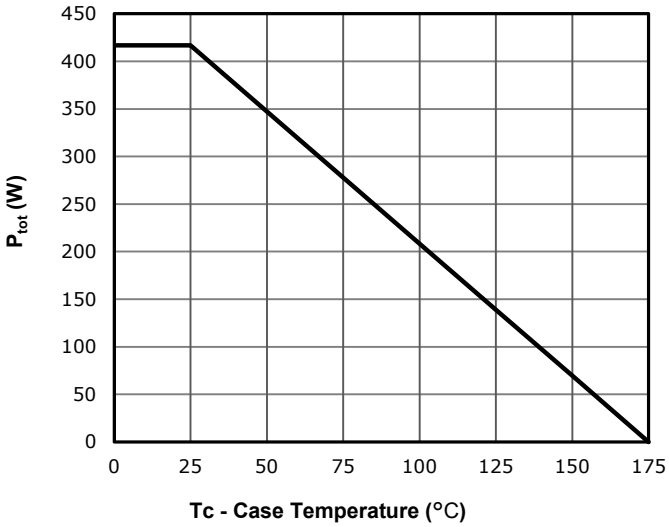
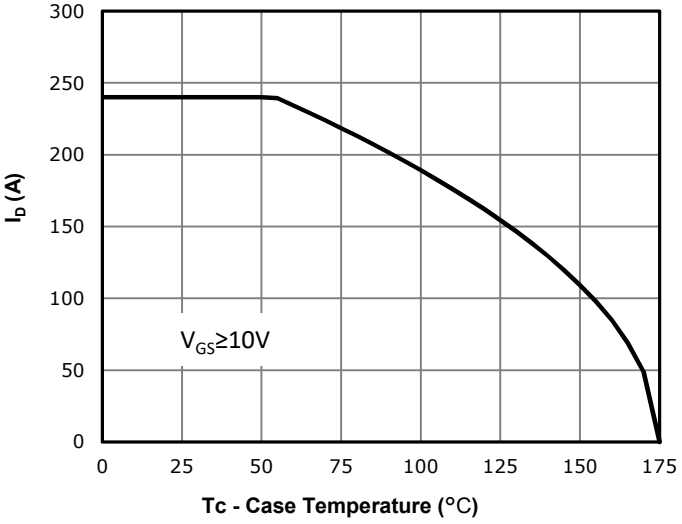


Fig 12: Drain Current Derating



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Fig 13: Safe Operating Area

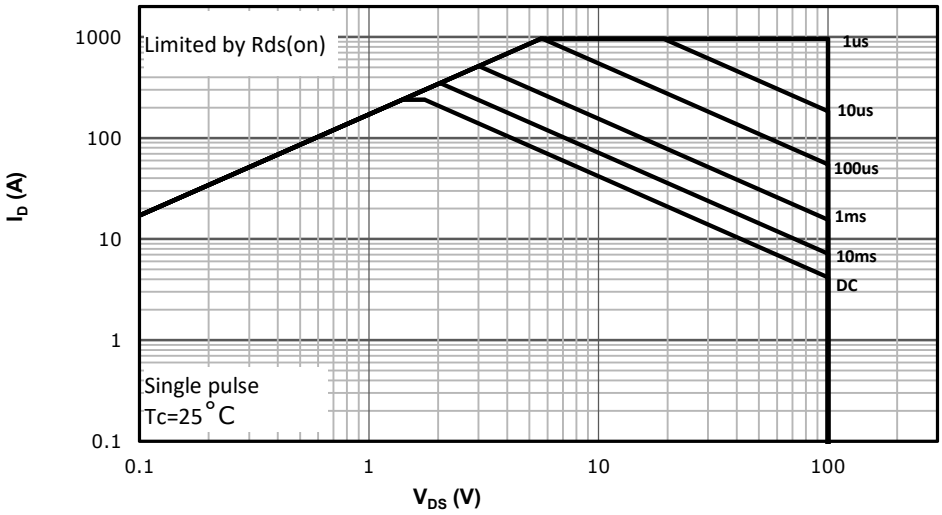
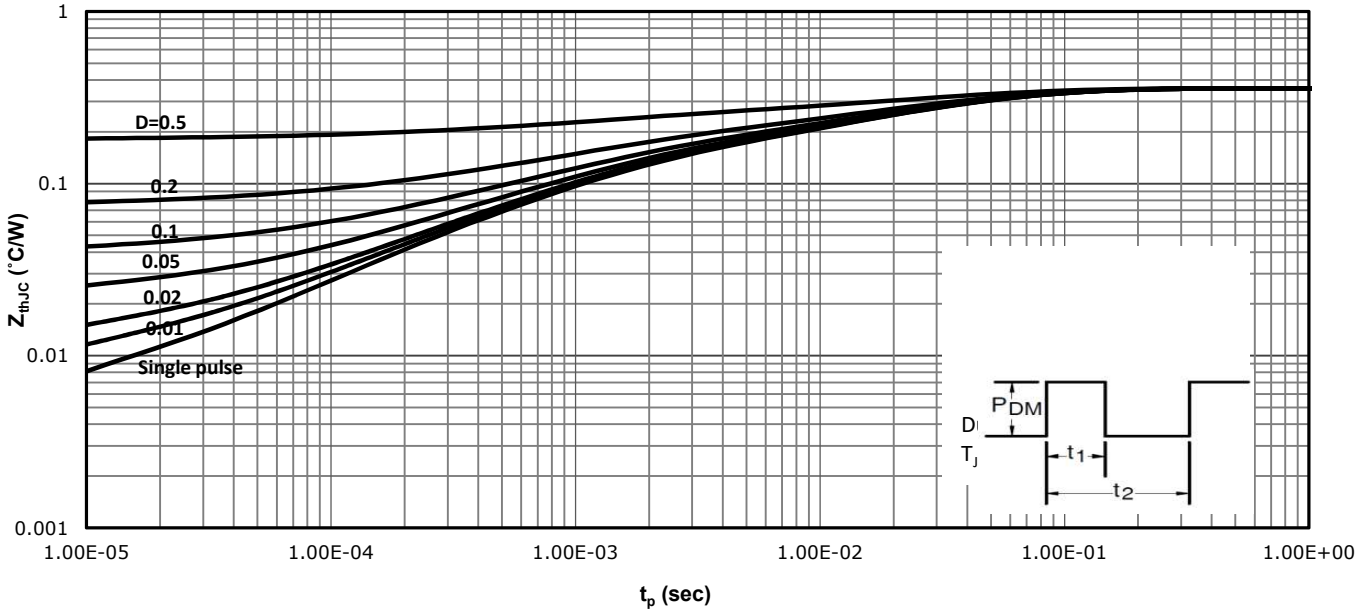


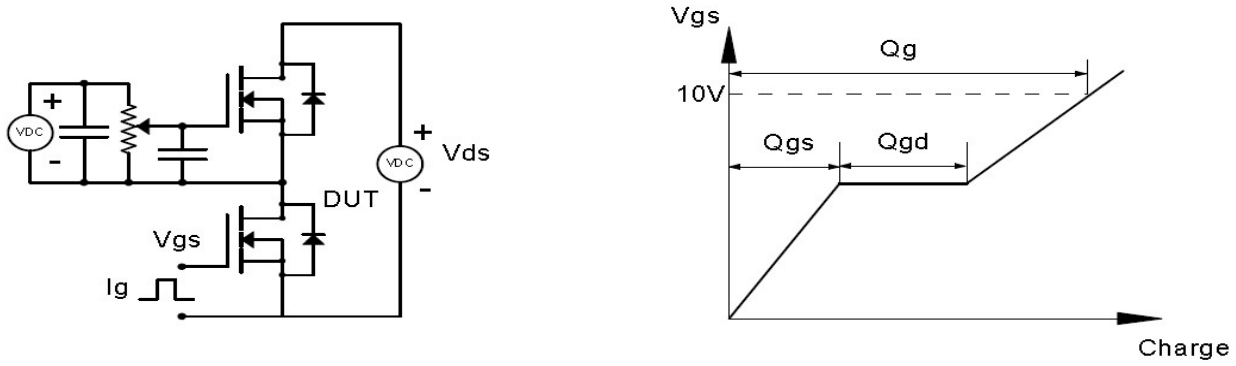
Fig 14: Max. Transient Thermal Impedance



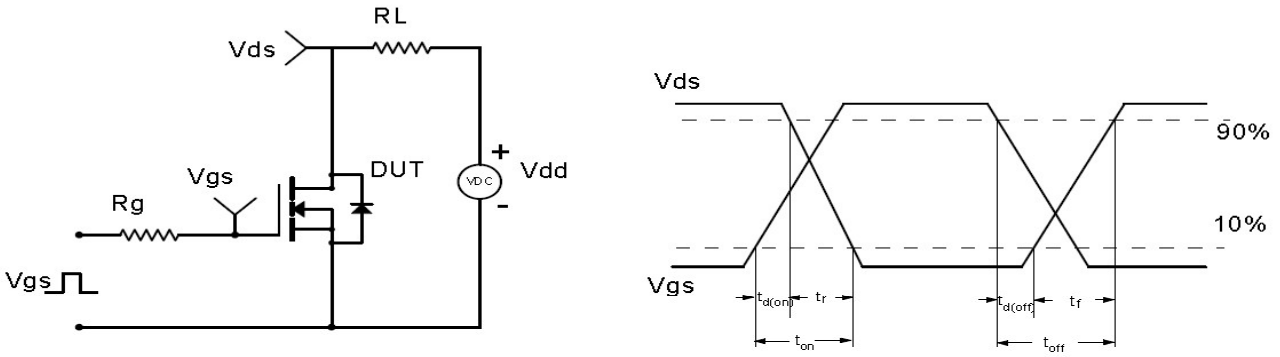
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Test Circuit & Waveform

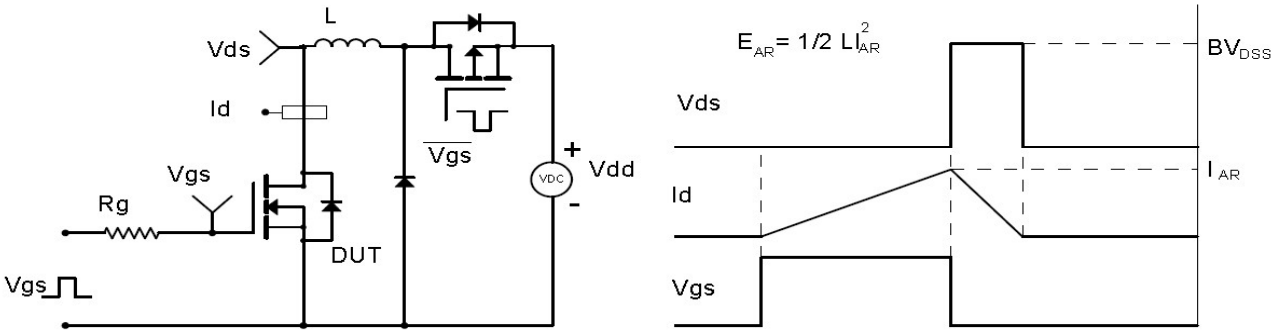
Gate Charge Test Circuit & Waveform



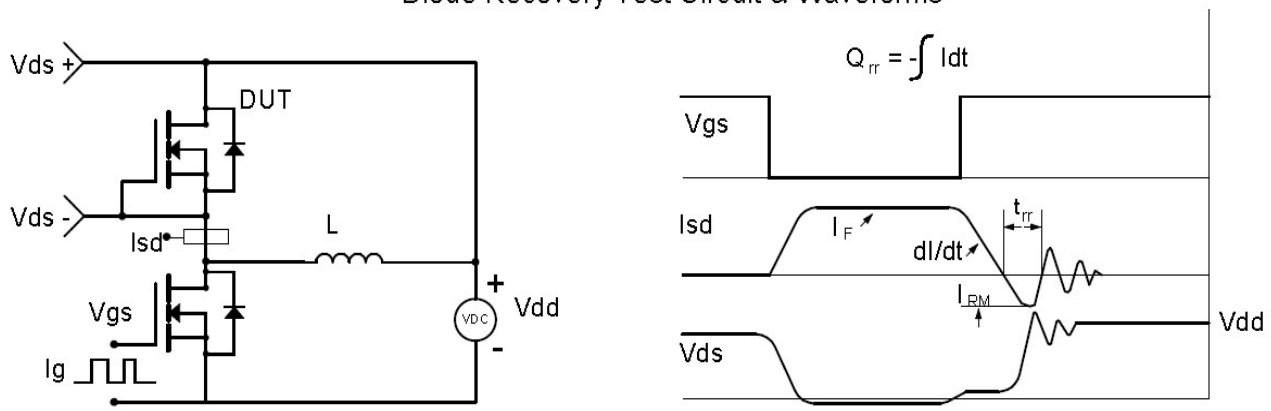
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

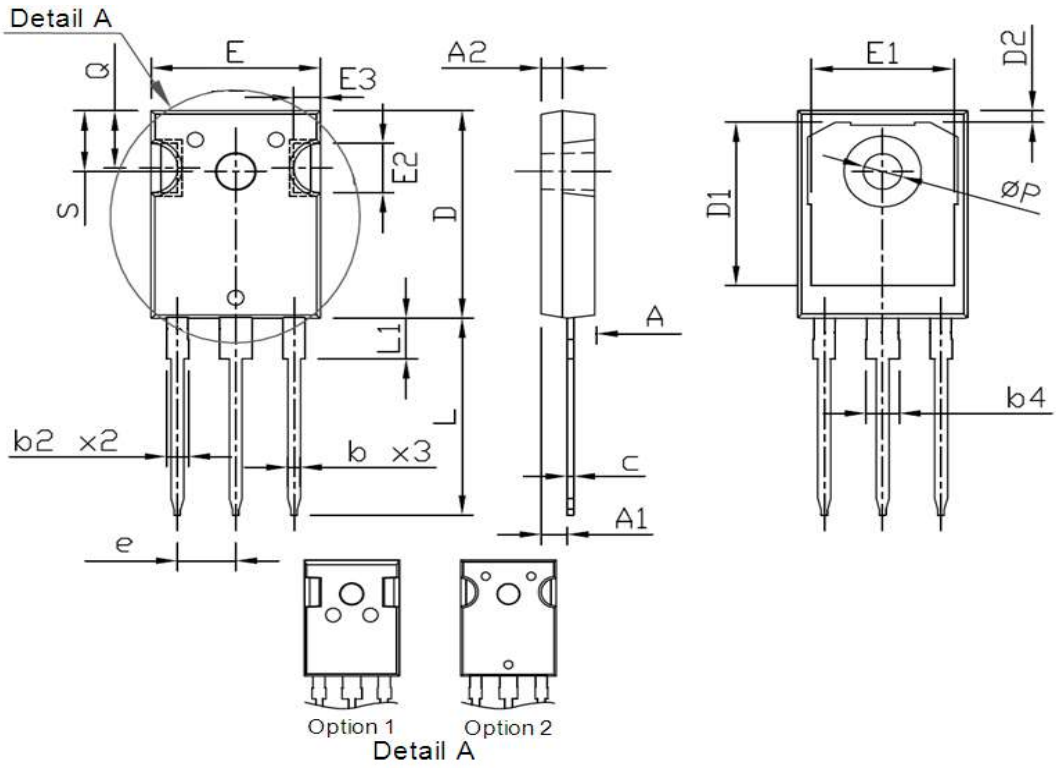


Diode Recovery Test Circuit & Waveforms



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Package Outline: TO-247



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	4.70	5.30	0.185	0.209
A1	2.20	2.60	0.087	0.102
A2	1.50	2.49	0.059	0.098
b	1.04	1.33	0.041	0.052
b2	1.90	2.41	0.075	0.095
b4	2.87	3.43	0.113	0.135
c	0.55	0.70	0.022	0.028
D	20.70	21.30	0.815	0.839
D1	16.25	17.65	0.640	0.695
D2	0.51	1.40	0.020	0.055
e	5.44 BSC.		0.214 BSC.	
E	15.50	16.30	0.610	0.642
E1	13.08	14.16	0.515	0.557
E2	3.80	5.49	0.150	0.216
E3	1.00	2.75	0.039	0.108
L	19.72	20.32	0.776	0.800
L1	3.85	4.50	0.152	0.177
Q	5.25	6.25	0.207	0.246
P	3.50	3.70	0.138	0.146
S	6.04	6.30	0.238	0.248

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Revision History

Revison	Date	Major changes
1.0	2022/12/28	Release of Preliminary version.
2.0	2023/3/12	Release of Formal version.
3.0	2023/10/7	Tjmax update to 175°C & Package Info update.
4.0	2024/3/20	Add VTH & BV Temperature Curve.
5.0	2024/6/21	Add IS , IS pulse

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.

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